

## **Electric pulse induced resistance switching in oxide– metal junctions**

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We investigate the electric pulse induced resistance switching in oxide-metal contacts at room temperature. Using a multiterminal configuration, we find a complementary effect where the contact resistance of electrodes at opposite ends -a non volatile memory device- exhibit variations of opposite sign, These reversible variations are further studied using different electric protocols, to show differences at each electrode. We discuss the mechanism driving the effect both on LaPrCaMnO and TiO samples contacted with Ag electrodes.